

ASME (American Society of Mechanical Engineers)

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출판사 소개 및 수록내용

□ 출판사 소개

기계공학 관련 한 American Society of Mechanical Engineers(ASME)는 Technical, educational and research issue를 추구하는 세계적인 Engineering Society 입니다.

□ 수록내용

■ 주제분야 : 기계공학

■ 제공연도: 1980 ~ 현재

■ 제공종수 : 25종 + AMR Journal







ASME Webpage: http://www.asmedl.org/

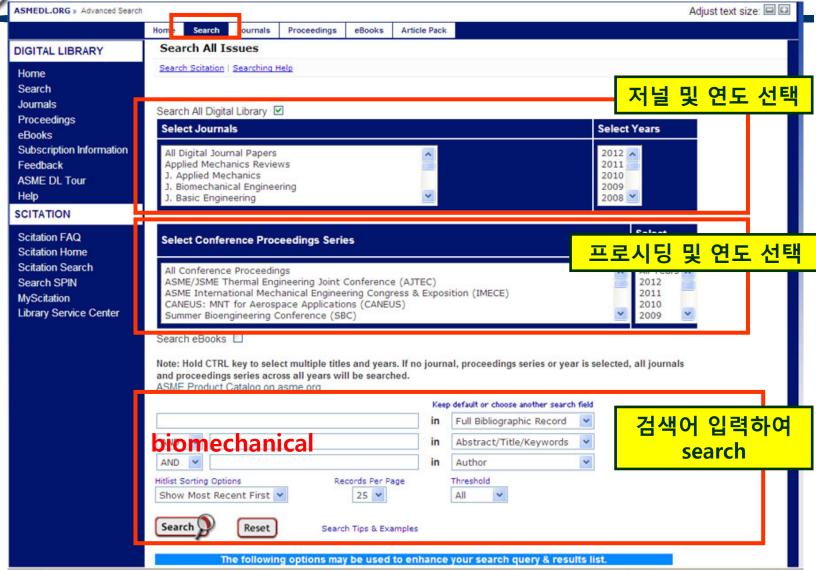








검색방법1









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검색방법1

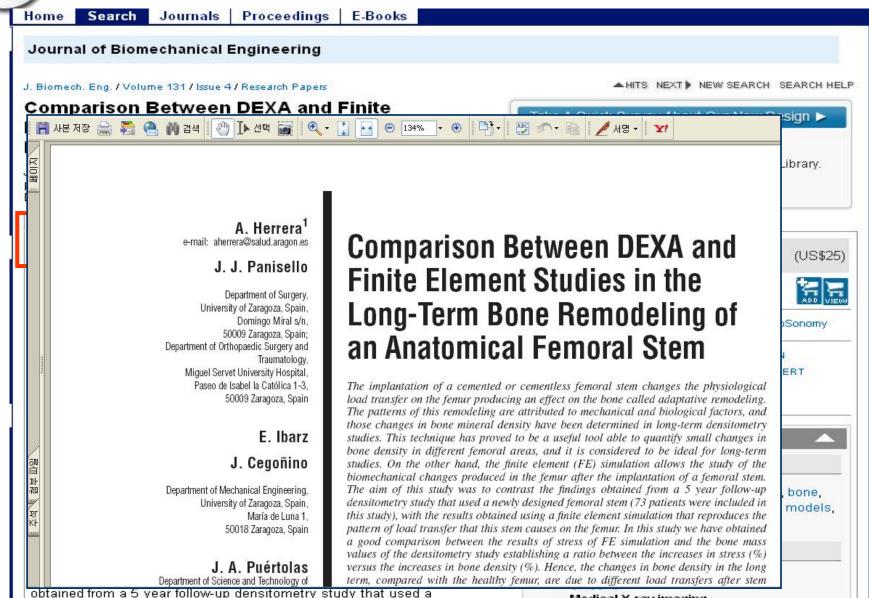
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검색방법1

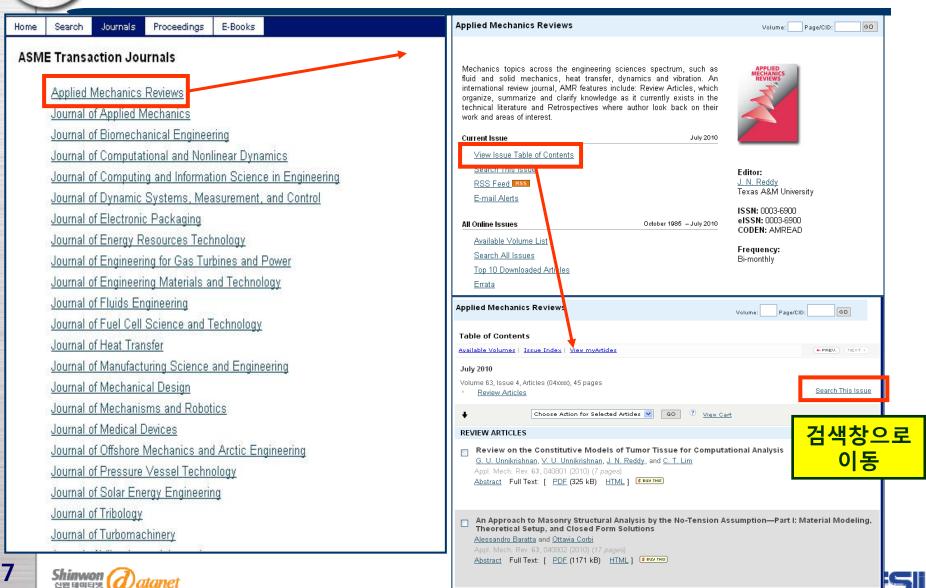
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Medical X-ray imaging



ASME Journals





Scitation 검색

- □ Scitation란? (http://scitation.aip.org)
 - 기존 AIP에서 제공하는 Online Journal Publishing Service(OJPS) 에서 re-launch된 Journal Hosting 업체로 AIP관련 Society에서 제공하는 저널을 검색하는 Portal Site이며 검색결과를 찾는 과정에서 저널명이나 출판사 등 단계적으로 원하는 Article로 접근하실수 있습니다.







검색방법 2 - Browse by Journal in Scitation

예제 1.

Journal of Electronic Packaging -October 2001Volume 123, Issue 4에서 Steven Chen and J.Albert Chiou가 저자인 Four Terminal Measurement and Simulations for Sheet Resistance in Piezoresistive Sensing Elements 이라는 Article을 찾고 싶을 때



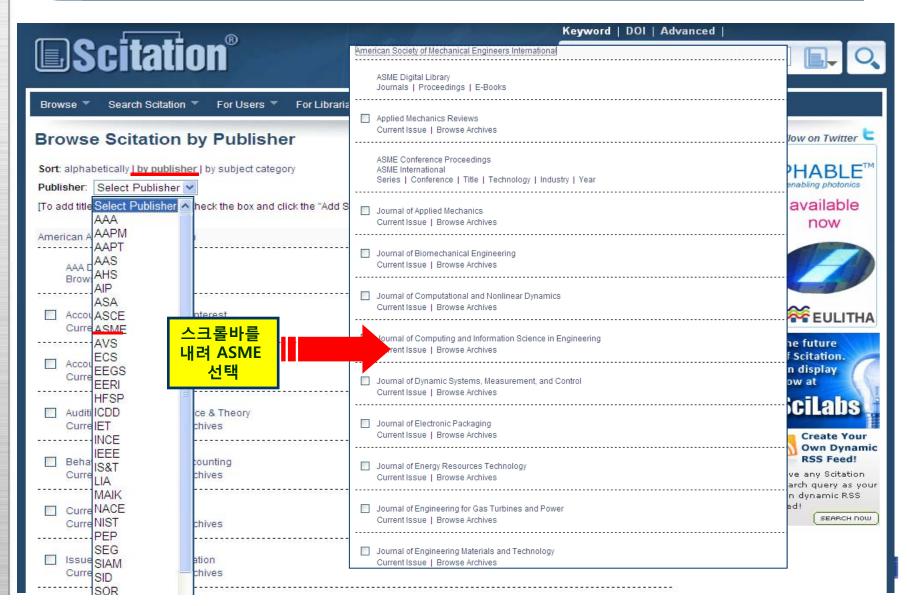






Scitation로 접속한 화면 (http://scitation.aip.org)





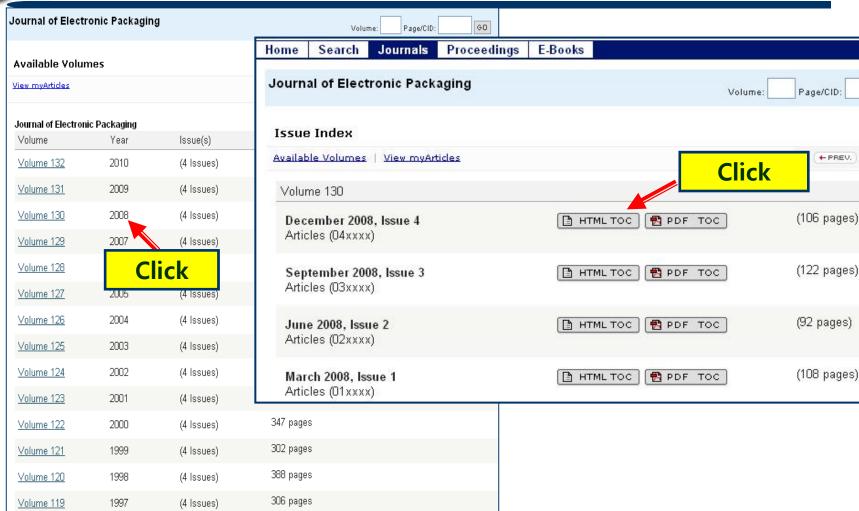




















PDF로 본 파일

Electromigration Reliability With Respect to Cu Weight Contents of Sn-Ag-Cu Flip-Chip Solder Joints **Under Comparatively Low Current** Stressing

This work presents electromigration reliability and patterns of Sn-3Ag-0.5Cu and Sn-3Ag-1.5Cu/Sn-3Ag-0.5Cu composite flip-chip solder joints with Ti/Ni(V)/Cu under bump metallurgy (UBM), bonded on Au/Ni/Cu substrate pads. The solder joints were subjected to an average current density of 5 kA/cm² under an ambient temperature of 150°C. Under the situation when electron charges flow from the UBM toward the substrate, Sn diffuses from the Cu-Ni-Sn intermetallic compound developed around the UBM toward the UBM and eventually causes the Ni(V) layer to deform. Electromigration reliability of Sn-3Ag-1.5Cu/Sn-3Ag-0.5Cu composite flip-chip solder joints was found to be better than that of Sn-3A2-0.5Cu solder joints. According to the morphological observations on cross-sectioned solder joints, a failure mechanism is proposed as follows. Since the deformation of the Ni(V) layer as a result of Sn diffusion toward the UBM is considered as the dominant failure, a greater Cu weight content in the solder joints would trap more Sn in the Sn-Cu interfacial reaction and would therefore retard the diffusion of Sn toward the UBM and hence enhance the electromigration reliability. [DOI: 10.1115/1.2957325]

Keywords: electromigration, flip-chip, solder joint, reliability, Sn-Ag-Cu, Cu weight



감사합니다



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